



Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 243317US3		SERIAL NO. 10/673,155	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Kazuyuki ICHIKAWA, et al.			
				FILING DATE September 30, 2003		GROUP 3679	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
B	AA	6,319,337	11/20/2001	K. YOSHIDA, et al.	-	-	
B	AB	4,275,571	06/30/1981	H.- H. WELSCHOF	-	-	
B	AC	3,024,626	03/13/1962	T. A. FRISCHMAN	-	-	
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
B	AO	1 016 801	07/05/2000	EUROPE <i>EPD</i>			
B	AP	2001-206004	07/31/2001	JAPAN (with English Abstract)			X
B	AQ	57-41840	03/09/1982	JAPAN (with English Abstract)			X
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW						
	AX						
	AY						
	AZ					<input type="checkbox"/> Additional References sheet(s) attached	
Examiner Greg Binda Patent Examiner				Date Considered 24 JAN 2005			
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Form PTO 1449
(Modified)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY DOCKET NO.
243317US3SERIAL NO. 10/673,155
New Application

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT
Kazuyuki ICHIKAWA, et al.FILING DATE
Herewith 9/30/2003GROUP
3679

U.S. PATENT DOCUMENTS

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	AA						
	AB						
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	AM						
	AN						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
Ⓟ	AO	9-42303	02/10/97	Japan (with English Abstract)		X
	AP					
	AQ					
	AR					
	AS					
	AT					
	AU					
	AV					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

	AW	
	AX	
	AY	
	AZ	

☐ Additional References sheet(s) attached

Examiner

Greg Binda
Patent Examiner

Date Considered

24 JAN 2005

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.